N-channel TrenchMOS standard level FET

Rev. 3 — 13 October 2010

Product data sheet

1. Product profile

1.1 General description

Standard level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using NXP High-Performance Automotive (HPA) TrenchMOS technology. This product has been designed and qualified to the appropriate AEC standard for use in automotive critical applications.

1.2 Features and benefits

- Q101 compliant
- Suitable for standard level gate drive sources

1.3 Applications

- 12 V, 24 V and 42 V loads
- Automotive systems
- DC-to-DC converters
- Engine management

1.4 Quick reference data

Table 1. Quick reference data

Symbol Parameter Conditions Min Max Unit Тур T_i ≥ 25 °C; T_i ≤ 175 °C V V_{DS} drain-source 100 voltage I_D drain current V_{GS} = 10 V; T_{mb} = 25 °C; 24.8 A see Figure 1; see Figure 4 T_{mb} = 25 °C; see <u>Figure</u> 2 P_{tot} total power 85 W _ dissipation Static characteristics drain-source $V_{GS} = 10 \text{ V}; \text{ I}_{D} = 10 \text{ A};$ 40 53 mΩ R_{DSon} on-state $T_i = 25 \text{ °C}; \text{ see } Figure 12;$ resistance see Figure 13



- Suitable for thermally demanding environments due to 175 °C rating
- General purpose power switching
- Solenoid drivers
- Transmission control

BUK7Y53-100B

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Table 1.	Quick reference da	tacontinued				
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Avalanch	e ruggedness					
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	$ \begin{split} I_D &= 24.8 \text{ A}; \text{V}_{\text{sup}} \leq 100 \text{ V}; \\ R_{\text{GS}} &= 50 \Omega; \text{V}_{\text{GS}} = 10 \text{ V}; \\ T_{j(\text{init})} &= 25 ^\circ\text{C}; \text{ unclamped} \end{split} $	-	-	81	mJ
Dynamic	characteristics					
Q_{GD}	gate-drain charge	$I_D = 10 \text{ A}; V_{DS} = 80 \text{ V};$ $V_{GS} = 10 \text{ V}; \text{ see } Figure 14$	-	8.5	-	nC

2. Pinning information

Table 2.Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	С	source		-
2	S	source	mb	
3	S	source		
4	G	gate		
mb	D	mounting base; connected to drain		mbb076 S
			SOT669 (LFPAK)	

3. Ordering information

Table 3.	Ordering in	formation		
Type num	ber	Package		
		Name	Description	Version
BUK7Y53-	100B	LFPAK	plastic single-ended surface-mounted package (LFPAK); 4 leads	SOT669

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4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

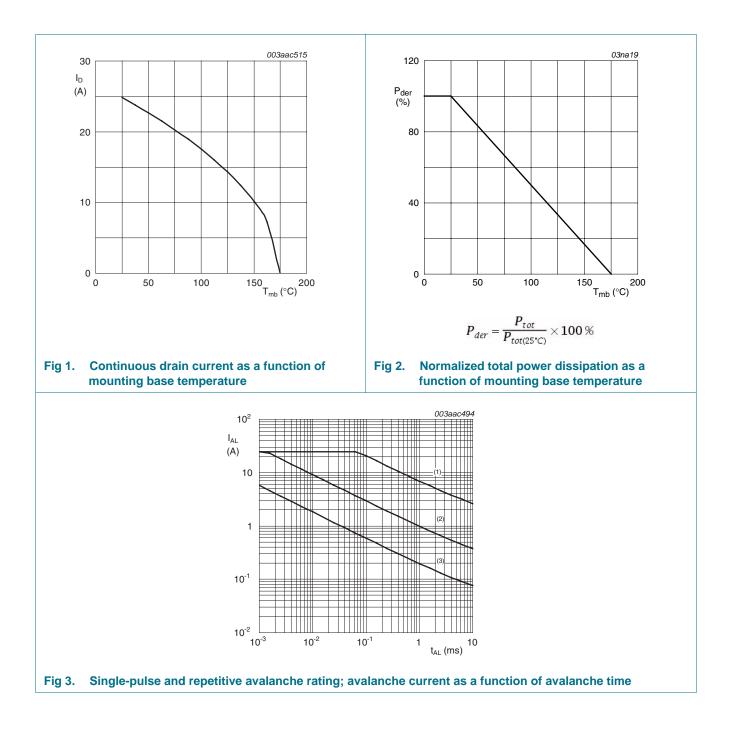
Parameter	Conditions		Min	Мах	Unit
drain-source voltage	T _j ≥ 25 °C; T _j ≤ 175 °C		-	100	V
drain-gate voltage	$R_{GS} = 20 \text{ k}\Omega$		-	100	V
gate-source voltage			-20	20	V
drain current	$T_{mb} = 25 \text{ °C}; V_{GS} = 10 \text{ V}; \text{ see } \frac{\text{Figure 1}}{\text{Figure 4}};$		-	24.8	А
	T_{mb} = 100 °C; V_{GS} = 10 V; see <u>Figure 1</u>		-	17.6	А
peak drain current	$T_{mb} = 25 \text{ °C}; t_p \le 10 \mu\text{s}; \text{ pulsed};$ see Figure 4		-	99	А
total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>		-	85	W
storage temperature			-55	175	°C
junction temperature			-55	175	°C
diode					
source current	T _{mb} = 25 °C		-	24.8	А
peak source current	$t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^{\circ}C$		-	99	А
ggedness					
non-repetitive drain-source avalanche energy	$\label{eq:ID} \begin{array}{l} I_{D} = 24.8 \; A; \; V_{sup} \leq 100 \; V; \; R_{GS} = 50 \; \Omega; \\ V_{GS} = 10 \; V; \; T_{j(init)} = 25 \; ^{\circ}C; \; unclamped \end{array}$		-	81	mJ
repetitive drain-source avalanche energy	see <u>Figure 3</u>	<u>[1][2][3]</u>	-	-	J
	drain-source voltage drain-gate voltage gate-source voltage drain current peak drain current total power dissipation storage temperature junction temperature diode source current peak source current ggedness non-repetitive drain-source avalanche energy repetitive drain-source	$\begin{array}{ccc} drain-source \mbox{ voltage } & T_j \geq 25 \ {}^\circ\mbox{C}; \ T_j \leq 175 \ {}^\circ\mbox{C} \\ drain-gate \mbox{ voltage } & R_{GS} = 20 \ k\Omega \\ gate-source \mbox{ voltage } & T_{mb} = 25 \ {}^\circ\mbox{C}; \ V_{GS} = 10 \ V; \ see \ Figure 1; \\ see \ Figure 4 \\ \hline T_{mb} = 100 \ {}^\circ\mbox{C}; \ V_{GS} = 10 \ V; \ see \ Figure 1 \\ peak \ drain \ current & T_{mb} = 25 \ {}^\circ\mbox{C}; \ t_p \leq 10 \ \mu s; \ pulsed; \\ see \ Figure 4 \\ \hline total \ power \ dissipation & T_{mb} = 25 \ {}^\circ\mbox{C}; \ see \ Figure 2 \\ storage \ temperature \\ junction \ temperature \\ \hline diode & \\ \hline source \ current & T_{mb} = 25 \ {}^\circ\mbox{C} \\ peak \ source \ current & T_{mb} = 25 \ {}^\circ\mbox{C} \\ peak \ source \ current & t_p \leq 10 \ \mu s; \ pulsed; \ T_{mb} = 25 \ {}^\circ\mbox{C} \\ \hline ggedness & \\ \hline non-repetitive \ drain-source & I_D = 24.8 \ A; \ V_{sup} \leq 100 \ V; \ R_{GS} = 50 \ \Omega; \\ V_{GS} = 10 \ V; \ T_{j(init)} = 25 \ {}^\circ\mbox{C}; \ unclamped \\ \hline repetitive \ drain-source & see \ Figure 3 \\ \hline \end{array}$	$\begin{array}{ccc} drain-source voltage & T_{j} \geq 25 \ ^{\circ}\text{C}; \ T_{j} \leq 175 \ ^{\circ}\text{C} & \\ drain-gate voltage & \\ R_{GS} = 20 \ \text{k}\Omega & \\ gate-source voltage & \\ \\ drain current & \\ T_{mb} = 25 \ ^{\circ}\text{C}; \ V_{GS} = 10 \ \text{V}; \ \text{see Figure 1}; & \\ & \text{see Figure 4} & \\ \hline T_{mb} = 100 \ ^{\circ}\text{C}; \ V_{GS} = 10 \ \text{V}; \ \text{see Figure 1} & \\ \hline peak \ drain \ current & \\ T_{mb} = 25 \ ^{\circ}\text{C}; \ t_{p} \leq 10 \ \text{\mu}\text{s}; \ \text{pulsed}; & \\ & \text{see Figure 4} & \\ \hline total \ power \ dissipation & \\ T_{mb} = 25 \ ^{\circ}\text{C}; \ \text{see Figure 2} & \\ \hline storage \ temperature & \\ & \text{junction temperature} & \\ \hline \textbf{diode} & \\ & \text{source \ current} & \\ T_{mb} = 25 \ ^{\circ}\text{C} & \\ & \text{peak \ source \ current} & \\ T_{mb} = 25 \ ^{\circ}\text{C} & \\ \hline peak \ source \ current & \\ & t_{p} \leq 10 \ \text{\mu}\text{s}; \ \text{pulsed}; \ T_{mb} = 25 \ ^{\circ}\text{C} & \\ \hline \textbf{ggedness} & \\ & \text{non-repetitive \ drain-source} & \\ & I_{D} = 24.8 \ \text{A}; \ V_{sup} \leq 100 \ \text{V}; \ R_{GS} = 50 \ \Omega; \\ & V_{GS} = 10 \ \text{V}; \ T_{j(init)} = 25 \ ^{\circ}\text{C}; \ \text{unclamped} & \\ \hline \textbf{fulcular} & \\ \hline fu$	$\begin{array}{cccc} drain-source voltage & T_j \geq 25 \ {}^\circ C; \ T_j \leq 175 \ {}^\circ C & - \\ drain-gate voltage & R_{GS} = 20 \ k\Omega & - \\ gate-source voltage & -20 \\ drain current & T_{mb} = 25 \ {}^\circ C; \ V_{GS} = 10 \ V; \ see \ Figure 1; \\ see \ Figure 4 \\ T_{mb} = 100 \ {}^\circ C; \ V_{GS} = 10 \ V; \ see \ Figure 1 & - \\ r_{mb} = 25 \ {}^\circ C; \ t_p \leq 10 \ \mu s; \ pulsed; \ see \ Figure 4 \\ \hline total \ power \ dissipation & T_{mb} = 25 \ {}^\circ C; \ see \ Figure 2 & - \\ storage \ temperature & -55 \\ junction \ temperature & -55 \\ \hline diode & & \\ source \ current & T_{mb} = 25 \ {}^\circ C; \ see \ Figure 2 & - \\ source \ current & T_{mb} = 25 \ {}^\circ C; \ see \ Figure 2 & - \\ source \ current & T_{mb} = 25 \ {}^\circ C & - \\ peak \ source \ current & t_p \leq 10 \ \mu s; \ pulsed; \ T_{mb} = 25 \ {}^\circ C & - \\ ggedness & & \\ non-repetitive \ drain-source & I_D = 24.8 \ A; \ V_{sup} \leq 100 \ V; \ R_{GS} = 50 \ \Omega; \\ v_{GS} = 10 \ V; \ T_{j(init)} = 25 \ {}^\circ C; \ unclamped \\ repetitive \ drain-source & see \ Figure 3 & \ \begin{array}{c} 11213 \ see \ Figure 3 & \ for \ repetitive \ reperimed \ repetitive \ repetitive \ repetitive \ reperimed \ repetitive \ repetitive \ reperimed \ repetitive \ reperimed \ repetitive \ repetitive \ reperimed \ repetitive \ reperimed \ repetitive \ reperimed \ repetitive \ reperimed \ reperimed \ repetitive \ reperimed \ repetitive \ reperimed \ reprimed \ reperimed \ reperimed \ reprimed \ re$	$\begin{array}{ccccccc} drain-source voltage & T_j \geq 25 \ {}^\circ C; \ T_j \leq 175 \ {}^\circ C & - & 100 \\ \hline drain-gate voltage & R_{GS} = 20 \ k\Omega & - & 100 \\ \hline gate-source voltage & -20 & 20 \\ \hline drain current & T_{mb} = 25 \ {}^\circ C; \ V_{GS} = 10 \ V; \ see \ Figure 1; \ see \ Figure 4 \\ \hline T_{mb} = 100 \ {}^\circ C; \ V_{GS} = 10 \ V; \ see \ Figure 1 & - & 17.6 \\ \hline peak \ drain \ current & T_{mb} = 25 \ {}^\circ C; \ t_p \leq 10 \ \mu s; \ pulsed; \ see \ Figure 4 \\ \hline total \ power \ dissipation & T_{mb} = 25 \ {}^\circ C; \ see \ Figure 2 & - & 85 \\ storage \ temperature & -55 & 175 \\ junction \ temperature & -55 & 175 \\ \hline diode & & & & \\ \hline source \ current & T_{mb} = 25 \ {}^\circ C & - & 24.8 \\ peak \ source \ current & T_{mb} = 25 \ {}^\circ C & - & 24.8 \\ peak \ source \ current & T_{mb} = 25 \ {}^\circ C & - & 24.8 \\ peak \ source \ current & T_{mb} = 25 \ {}^\circ C & - & 24.8 \\ peak \ source \ current & T_{mb} = 25 \ {}^\circ C & - & 24.8 \\ peak \ source \ current & T_{mb} = 25 \ {}^\circ C & - & 24.8 \\ peak \ source \ current & T_{mb} = 25 \ {}^\circ C & - & 24.8 \\ peak \ source \ current & T_{mb} = 25 \ {}^\circ C & - & 24.8 \\ peak \ source \ current & T_{mb} = 25 \ {}^\circ C & - & 24.8 \\ peak \ source \ current & T_{mb} = 25 \ {}^\circ C & - & 24.8 \\ peak \ source \ current & T_{mb} = 25 \ {}^\circ C & - & 24.8 \\ peak \ source \ current & T_{mb} = 25 \ {}^\circ C & - & 24.8 \\ peak \ source \ current & T_{mb} = 25 \ {}^\circ C & - & 24.8 \\ peak \ source \ current & T_{mb} = 25 \ {}^\circ C & - & 24.8 \\ peak \ source \ current & T_{mb} = 25 \ {}^\circ C & - & 24.8 \\ peak \ source \ current & T_{mb} = 25 \ {}^\circ C & - & 99 \\ produe \ source \ current & T_{mb} = 24.8 \ {}^\circ C & C & - & 24.8 \\ peak \ source \ current & T_{mb} = 24.8 \ {}^\circ C & C & - & 99 \\ produe \ current $

[1] Single-pulse avalanche rating limited by maximum junction temperature of 175 °C.

[2] Repetitive avalanche rating limited by an average junction temperature of 170 °C.

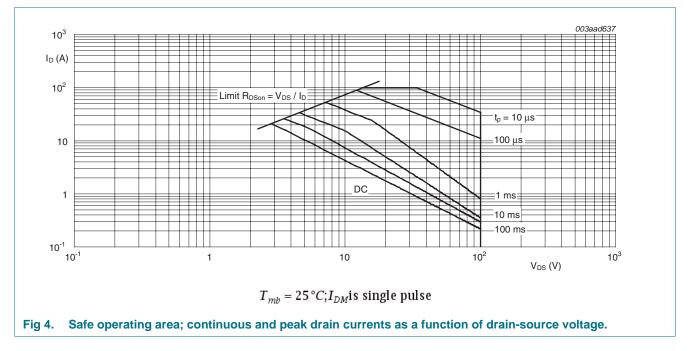
[3] Refer to application note AN10273 for further information.

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5. Thermal characteristics

Table 5.Thermal characteristics

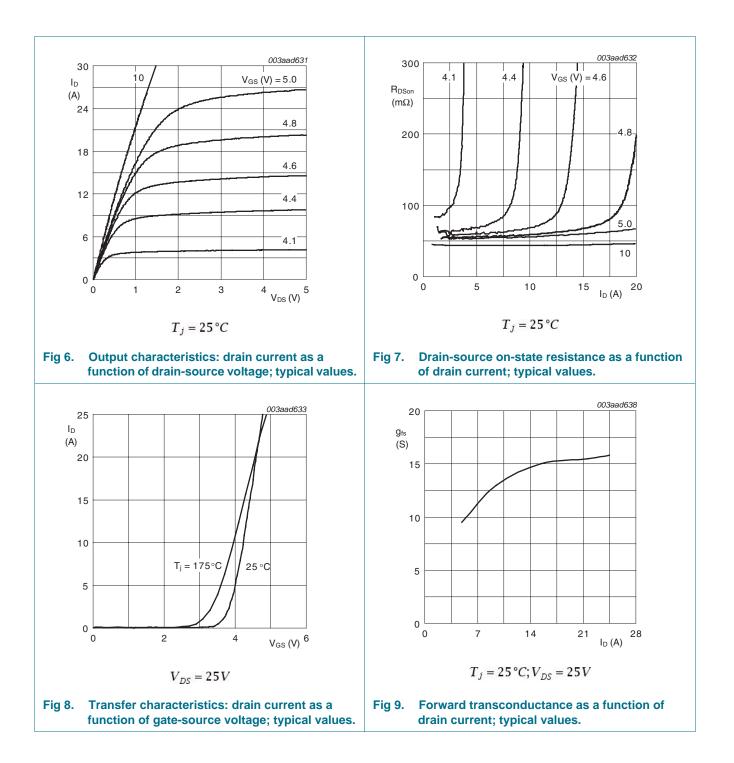


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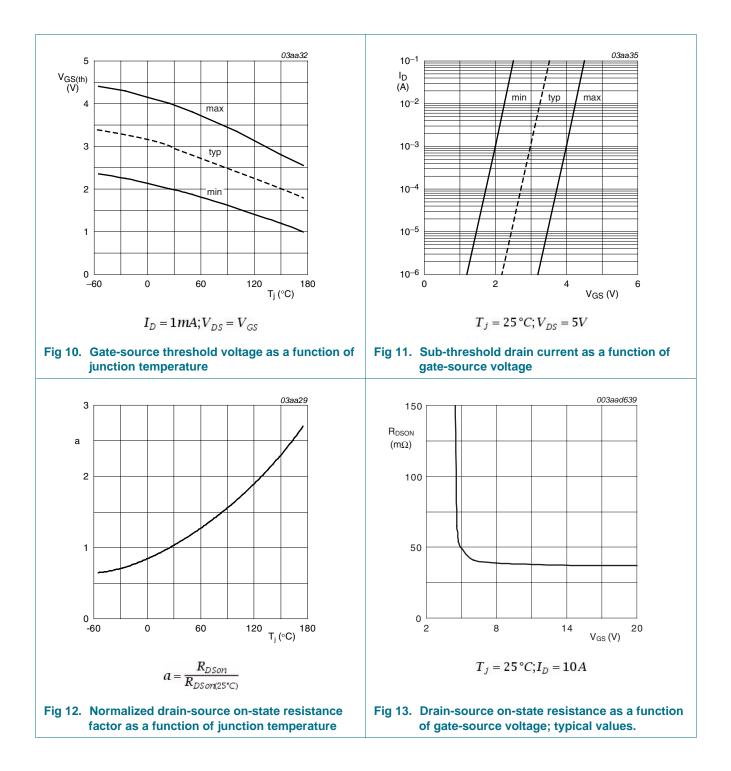
6. Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
-	aracteristics					
V _{(BR)DSS}	drain-source	I _D = 250 μA; V _{GS} = 0 V; T _i = 25 °C	100	-	-	V
	breakdown voltage	$I_D = 250 \ \mu\text{A}; V_{GS} = 0 \ \text{V}; T_i = -55 \ \text{°C}$	90	-	-	V
V _{GS(th)}	gate-source threshold voltage	$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 25 \text{ °C};$ see Figure 10; see Figure 11	2	3	4	V
		I _D = 1 mA; V _{DS} = V _{GS} ; T _j = -55 °C; see <u>Figure 10</u>	-	-	4.4	V
		I _D = 1 mA; V _{DS} = V _{GS} ; T _j = 175 °C; see <u>Figure 10</u>	1	-	-	V
I _{DSS}	drain leakage current	V_{DS} = 100 V; V_{GS} = 0 V; T_j = 25 °C	-	0.02	1	μΑ
		V _{DS} = 100 V; V _{GS} = 0 V; T _j = 175 °C	-	-	500	μA
I _{GSS}	gate leakage current	V _{DS} = 0 V; V _{GS} = 20 V; T _j = 25 °C	-	2	100	nA
		V _{DS} = 0 V; V _{GS} = -20 V; T _j = 25 °C	-	2	100	nA
R _{DSon}	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 10 \text{ A}; T_j = 175 ^{\circ}\text{C};$ see <u>Figure 12</u> ; see <u>Figure 13</u>	-	-	138	mΩ
		V _{GS} = 10 V; I _D = 10 A; T _j = 25 °C; see <u>Figure 12</u> ; see <u>Figure 13</u>	-	40	53	mΩ
Dynamic	characteristics					
Q _{G(tot)}	total gate charge	$I_D = 10 \text{ A}; V_{DS} = 80 \text{ V}; V_{GS} = 10 \text{ V};$	-	22	-	nC
Q _{GS}	gate-source charge	see Figure 14	-	4.3	-	nC
Q _{GD}	gate-drain charge		-	8.5	-	nC
C _{iss}	input capacitance	$V_{GS} = 0 V; V_{DS} = 25 V; f = 1 MHz;$	-	1100	1467	pF
C _{oss}	output capacitance	T _j = 25 °C; see <u>Figure 15</u>	-	142	170	pF
C _{rss}	reverse transfer capacitance		-	63	86	pF
t _{d(on)}	turn-on delay time	$V_{DS} = 30 \text{ V}; \text{ R}_{L} = 3 \Omega; \text{ V}_{GS} = 10 \text{ V};$	-	15.3	-	ns
t _r	rise time	$R_{G(ext)} = 10 \ \Omega$	-	7.8	-	ns
t _{d(off)}	turn-off delay time		-	34	-	ns
t _f	fall time		-	7.7	-	ns
Source-d	rain diode					
V _{SD}	source-drain voltage	I _S = 15 A; V _{GS} = 25 V; T _j = 25 °C; see <u>Figure 16</u>	-	0.85	1.2	V
t _{rr}	reverse recovery time	$I_{S} = 20 \text{ A}; \text{ dI}_{S}/\text{dt} = -100 \text{ A}/\mu\text{s}; \text{ V}_{GS} = 0 \text{ V};$	-	56	-	ns
Q _r	recovered charge	V _{DS} = 30 V	-	155	-	nC

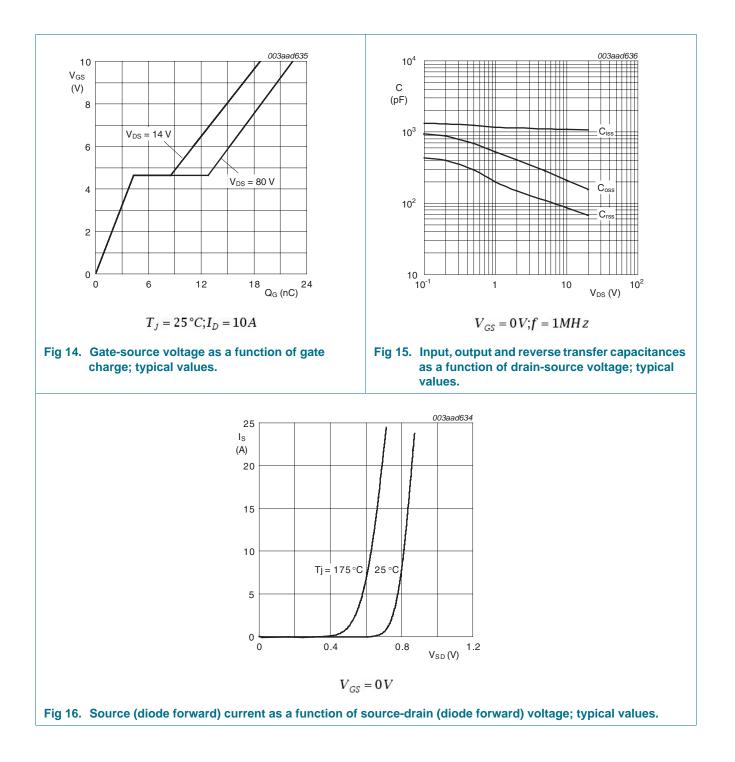
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7. Package outline

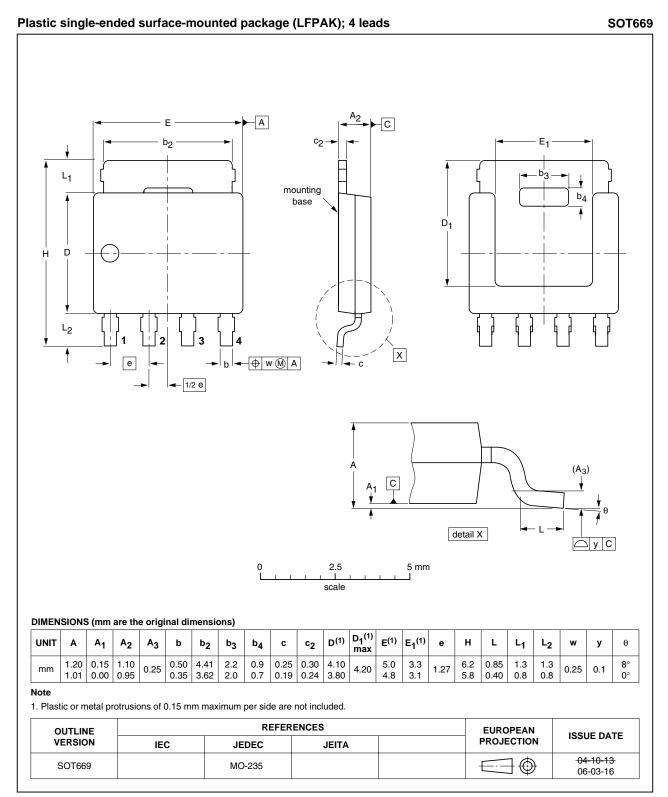


Fig 17. Package outline SOT669 (LFPAK)

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8. Revision history

Table 7. Revision	history			
Document ID	Release date	Data sheet status	Change notice	Supersedes
BUK7Y53-100B v.3	20101013	Product data sheet	-	BUK7Y53-100B_2
Modifications:	 Status change 	ed from objective to product.		
BUK7Y53-100B_2	20100211	Objective data sheet	-	BUK7Y53-100B_1

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9. Legal information

9.1 Data sheet status

Document status[1][2]	Product status ^[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions".

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